

Product Change Notification - KSRA-06EXYG135

Date: 23 Sep 2017
Product Category: 8-bit PIC Microcontrollers
Notification subject: CCB 3104 Initial Notice: Qualification of MTAI as an additional Final Test site for selected Atmel ATMEGA products available in 32L TQFP package
Notification text: **PCN Status:** Initial notification.

Microchip Parts Affected:
 Please open the attachments found in the attachments field below labeled as PCN_#_Affected_CPN.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:
 Qualification of MTAI as an additional Final Test site for selected Atmel products where the CPN begins with ATMEGA available in 32L TQFP package

Pre Change:
 Tested at LPI and ANAP final test site.

Post Change:
 Tested at LPI, ANAP and MTAI final test site.

Pre and Post Change Summary:

	Pre Change		Post Change		
Final test site	LPI	ANAP	LPI	ANAP	MTAI

Impacts to Data Sheet:
 None

Change Impact:
 None

Reason for Change:
 To improve on-time delivery performance by qualifying MTAI as new final test site.

Change Implementation Status:
 In Progress

Estimated Qualification Completion Date:
 October 2017

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

Time Table Summary:

	September 2017					October 2017				
Workweek	35	36	37	38	39	40	41	42	43	44
Initial PCN Issue Date				X						
Qual Report Availability							X			
Final PCN Issue Date							X			

Method to Identify Change:
 Traceability code.

Qualification Plan:
 Please open the attachments included with this PCN labeled as PCN_#_Qual Plan.

Revision History:
September 23, 2017: Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s): [PCN_KSRA-06EXYG135_Affected CPN.pdf](#)
[PCN_KSRA-06EXYG135_Qual_Plan.pdf](#)
[PCN_KSRA-06EXYG135_Affected CPN.xlsx](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

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KSRA-06EXYG135 -Qualification of MTAI as an additional Final Test site for selected Atmel products where the CPN begins with ATMEGA available in 32L TQFP package.

Affected Catalog Part Numbers (CPN)

PCN_KSRA-06EXYG135
Catalog Part Numbers
ATMEGA168PA-AU
ATMEGA168PA-AUR
ATMEGA328P-AU
ATMEGA328P-AUR
ATMEGA48PA-AU
ATMEGA48PA-AUR
ATMEGA88PA-AU
ATMEGA88PA-AUR
ATMEGA8A-AU
ATMEGA8A-AUR



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QUALIFICATION PLAN SUMMARY

PCN #: KSRA-06EXYG135

Date

September 1, 2017

**Qualification of MTAI as an additional Final Test site for
selected Atmel products where the CPN begins with
ATMEGA available in 32L TQFP package**

Purpose: Qualification of MTAI as an additional Final Test site for selected Atmel products where the CPN begins with ATMEGA available in 32L TQFP package

CCB No: 3104

Correlation Criteria:

Test / Evaluation	Test Conditions / Parameters
Datalog/Bin Comparison	Compare test numbers, test names, test sequence bin assignments & pass/fail results Accept if all match or justify the differences
Site by site verification	Verifies the channel map has the correct site assignments and tester/handler communications work correctly
Correlation lot report	Yield at each step and reject analysis between systems. 5K units are tested for each program conversion we perform. Accept on yield match within 1%
Unit to unit parametric correlation	A full assembly strip characterized on both systems and graphed vs each other & the data sheet limits
Test stability verification	50 loop test performed with no datalog delays Accept on 0 fails
Parametric test stability verification	Use Real Time Statistics software to create report of all parametric tests